# Pulse and hold strategy for sw itch ing current $m$ easurem ents 

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#### Abstract

W e investigate by theory and experim ent, the Josephson junction sw itch ing current detector in an environm ent $w$ ith frequency dependent dam ping. A nalysis of the circuit's phase space show that a favorable topology for sw itching can be obtained w ith overdam ped dynam ics at high frequencies. A pulse-and hold $m$ ethod is described, where a fast sw itch pulse brings the circuit close to an unstable point in the phase space when biased at the hold level. Experim ents are perform ed on Cooper pair transistors and $Q$ uantronium circuits, which are overdam ped at high frequencies with an on-chip RC shunt. For 20 $\mu \mathrm{s}$ sw itch pulses the sw $i t c h i n g$ process is well described by them al equilibrium escape, based on a generalization of $K$ ram ens form ula to the case of frequency dependent dam ping. A capacitor bias m ethod is used to create very rapid, 25 ns sw itch pulses, where it is observed that the sw itching process is not govemed by them al equilibrium noise.


## I. IN TRODUCTION

A classical non-linear dynam ical system, when driven to a point of instability, w ill undergo a bifurcation, where the system evolves tow ard distinctly di erent nalstates. At bifurcation the system becom es very sensitive and the $s m$ allest uctuation can determ ine the evolution of a m assive system w ith huge potential energy. This property of in nite sensitivity at the point of instability can be used to am plify very weak signals, and has recently been the focus of investigation in the design of quantum detectors to readout the state of quantum bits (qubits) built from Josephson junction (JJ) circuits. Here we exam ine in experim ent and theory a pulse and hold strategy for rapid sw itching of a JJ circuit which is quickly brought near a point of instability, pointing out several im portant properties for an ideal detector. $W$ e focus on sw itching in a circuit w ith overdam ped phase dynam ics at high frequencies, and underdam ped at low frequencies. $T$ his HF-overdam ped case is relevant to experim ents on sm all capacitance JJs biased $w$ ith typical $m$ easurem ent leads.

C lassical JJs have strongly non-linear electrodynam ics and they have served as a model system in non-linear physics for the last 40 years. M ore recently it has been shown that JJ circuits $w$ ith $s m$ all capacitance can also exhibit quantum dynam ics when properly m easured at low enough tem peratures. Experim ental dem onstration of the $m$ acroscopic quantum dynam ics in these circuits has relied on e cient quantum $m$ easurem ent strategies, characterized by high single shot sensitivity w ith rapid reset tim e and low back action. Som e of these $m$ easure$m$ ent or detection $m$ ethods are based on the sw itching of a JJ circuit from the zero voltage state to a nite voltage state. $1,2,3,4$ O ther detection $m$ ethods are based on a dispersive technique, where a high frequency signal probes the phase dynam ics of a qubit $5,6,7,8,9,10,11,12 \mathrm{~T}$ hese dispersive $m$ ethods have achieved the desired sensitivity
at considerably higher speeds than the static sw itching $m$ ethods, allow ing individual quantum $m$ easurem ents to be $m$ ade $w$ th $m$ uch higher duty cycle. In particular, the dispersive $m$ ethods have shown that it is possible to continuously m onitor the qubit ${ }^{13} \mathrm{H}$ ow ever, for both static sw itching and dispersive $m$ ethods, the sensitivity of the technique is im proved by exploiting the non-linear properties of the readout circuit in a pulse and hold m easurem ent strategy. This im proved sensitivity of the pulse and hold m ethod is not surprising, because when properly designed, the pulse and hold technique w ill exploit the in nite sensitivity of a non-linear system at the point of instability.

The general idea of exploiting the in nite sensitivity at an instable point is a recurrent them e in applications of non-linear dynam ics. T he basic idea has been used since the early days ofm icrow ave engineering in the wellknown param etric ampli er ${ }^{14}$ which has in nite gain at the point of dynam ical instability. The unstable point can be conveniently represented as a saddle point for the phase space tra jectories of the non-linear dynam icalsystem. In the pulse and hold $m$ easurem ent $m$ ethod an initial fast pulse is used to quickly bring the system to the saddle point for a particular hold bias level. The hold level is chosen so that the phase space topology favors a rapid separation in to the tw o basins of attraction in the phase space. The initialpulse should be not so fast that it w ill cause excessive back action on the qubit, but not so slow that it's duration exceeds the relaxation tim e of the qubit. The length of the hold pulse is that which is required to achieve a signal to noise ratio necessary for unam biguous determ ination of the resulting basin of attraction. In practice this length is set by the lters and ampli ers in the second stage of the quantum $m$ easure$m$ ent system.

In this paper we discuss pulse and hold detection in the context of sw itching from the zero voltage state to the nite voltage state of a JJ. W e give an overview of
such sw itching in JJs，focusing on the HF－overdam ped case．Sw itching detectors $w$ ith overdam ped high fre－ quency phase dynam ics are di erent from allother qubit $m$ easurem ent strategies im plem ented thus far，where un－ derdam ped phase dynam ics has been used．H ow ever，the H F－overdam ped case is quite relevant to a large num ber of experim ents which $m$ easure $s w$ itching in low capaci－ tance JJs w ith sm all critical currents $15,16,17,18 \mathrm{~W}$ e show that by $m$ aking the dam ping at high frequencies large enough，a favorable phase space topology for sw itching can be achieved． 19 In this overdam ped situation the ex－ temalphase can be treated classically and contributions ofm acroscopic quantum tunneling（ $\mathrm{M} Q \mathrm{~T}$ ）to the switch－ ing probability can be neglected，in contrast to the un－ derdam ped case． 20 E xperim entalresults are show $n$ where on－chip RC dam ping circuits are used to create an HF－ overdam ped environm ent．W e observe that for longer pulses of duration $20 \mu \mathrm{~s}$ ，the sw itching process is initi－ ated by therm al uctuations in the overdam ped system and therm alequilibrium is achieved at the base tem per－ ature of the cryostat（ 25 mk ）．For short pulses of du－ ration＜ 25 ns ，the switching is una ected by therm al uctuations up to a tem perature of 500 mK ，and the w idth of the sw itching distribution at low tem peratures is rather determ ined by random variations in the repeated sw itch pulse．A though the detector apparently had the speed and sensitivity required for $m$ aking a quantum $m$ easurem ent，we were unfortunately unable to dem on－ strate quantum dynam ics of the qubit due to problem s w th uctuating background charges．

## II．PHASE SPACE PORTRAITS

The non－linear dynam ics ofa D C－driven JJ can be pic－ torially represented in a phase space portrait．W e begin by exam ining the phase space portraits of the resistive and capacitively shunted junction（RCSJ），which is the sim plest $m$ odel from which we can gain intuitive under－ standing of the non－linear dynam ics．The RCSJ m odel consists of an ideal Josephson elem ent of critical current $I_{0}$ biased at the current level I，which is shunted by the parallelplate capacitance of the tunnel junction，$C_{J}$ and a resistor $R$ ，which $m$ odels the dam ping at all frequen－ cies（see g．$⿴ 囗 ⿱ 一 一 廾$（a））．The circuit param eters de ne the tw o quantities $!_{p}=P \overline{I_{0}={ }^{\prime}{ }_{0} \mathrm{C}_{J}}$ called the plasm a fre－ quency，and the quality factor $Q=!{ }_{p} R C . T$ he dynam ics is classi ed as overdam ped or underdam ped for $Q<1$ or $Q>1$ ，respectively．Here＇ $0=h=2 e$ is the reduced ux quantum．

The circuit dynam ics can be visualized by the $m$ otion of a particle of $m$ ass ${ }_{0}^{2} \mathrm{C}$ in a tilted washboard poten－ tial U（ ）$=\mathrm{E}_{\mathrm{J}}(\mathrm{i}+\cos )$ subjected to the dam ping force＇${ }_{0}^{2}=\mathrm{R}$ ，where the particle position corresponds to the phase di erence across the junction and the tilt $i$ is the applied current nom alized by the critical cur－ rent，$i=I=I_{0}$（see $\left.g 2(a)\right)$. Below the critical tilt $i=1$ the ctitious particle will stay in a localm in im um of the
（a）

（b）


FIG．1：（a）RCSJ m odel of a Josephson junction．（b）Sim－ ple model of a junction em bedded in an environm ent with frequency dependent im pedance．
washboard potential（ $m$ arked $A$ in $g$ 2（a））correspond－ ing to the superconducting state where $V=h-i=0$ ． Increasing the tilt of the potential to i＞1，where local $m$ inim a no longer exist，the particle w ill start to accel－ erate to a nite velocity $V=h-i>0$ determ ined by the dam ping．If the tilt is then decreased below $i=1$ ，the particle for an underdam ped JJ $(Q>1)$ will keep on $m$ oving due to inertia．Further decreasing the tilt below the level $i<i_{r}$ ，where loss per cycle from dam ping ex－ ceeds gain due to inertia，the particle will be retrapped in a localm inim um．In term s of the current－voltage char－ acteristic，this corresponds to hysteresis，or a coexistence of two stable states，$V=0$ and $V>0$ for a bias xed in the region $i_{x}<i<1$ ．For the overdam ped RCSJ m odel the particle will alw ays be trapped in a localm inim um for $i \quad 1$ and freely evolving dow $n$ the potential for $i>1$ and there is no coexistence of tw o stable states．

A phase space portrat ${ }^{19,21,22}$ of the RCSJ model is shown in 9 ．（2）．（b）．This portrait show $s$ tra jectories that the particle would follow in the space of coordinate（ ） versus velocity $(\rightarrow$ for a few chosen initial conditions． T he topology of the phase space portrait is characterized by severaldistinct features． F ix point attractors $m$ arked $\backslash A "$ in $g .2$ correspond to the particle resting in a $10-$ calm inim um of the w ashboard potential，and the saddle points $m$ arked $\backslash S$＂corresponds to the particle resting in an unstable state at the top of the potentialbarrier（com－ pare with g． 2 （a））．Two trajectories surrounding A and ending at $S$ are the unstable trajectories which de ne the boundary of a basin of attraction：A ll initial condi－ tionsw thin this boundary w ill follow a tra jectory leading to $A$ ．We call this the $0-b$ asin of attraction．The thick line $B$ is a stable lim iting cycle，corresponding to a free－ running state of the phase，where the circuit is under－ going Josephson oscillations with frequency ！$=\mathrm{V}={ }^{\prime}{ }_{0}$ ． A 11 trajectories leading to the lim iting cycle B start in
the 1 -basin of attraction, which is the region outside the 0 -basins. The existence of tw o basins of attraction in the phase space topology, and in particular the clear separation ofall 0 -basinsby the 1 -basin, $m$ ake the underdam ped RCSJ circuit ( $Q>1$ ) appropriate for a sw itching current detector, as we discuss below. For the overdam ped R C SJ circuit ( $\mathrm{Q}<1$ ) attractors A and B do not coexist for any xed bias condition, and it therefore can not be used for a sw itching current detector. H ow ever, the RCSJ m odel is not alw ays the $m$ ost realistic $m$ odel for the dynam ics of JJ circuits, as the dam ping in real experim ents is usually frequency dependent, and in the case ofsm all capacitance JJs, this frequency dependence can very m uch change the character of the dam ping.

At high frequencies of the order of the plasm a frequency of the junction (20-100 G H z for $\mathrm{Al} / \mathrm{A} 10 \mathrm{x} / \mathrm{A}$ ltunnel junctions) losses are typically due to radiation phenom ena, where the leads to the junction act as a wave guide for the $m$ icrow ave radiation. If $w e m$ odel the leads as a transm ission line, the high frequency im pedance would correspond to a dam ping resistance of the order of free space im pedance $Z \quad Z_{0}=2=60$. W ith the sm all capacitance of a typical JJ as used in present experim ents, this dam ping inevitably leads to overdam ped dynam ics $Q<1$. It should be noted that for sm all capacitance JJs, underdam ped phase dynam ics is hard to achieve in practice as high im pedance all the way up to the plasm a frequency is desired, and this requires an engineering e ort where the high im pedance leads need to be constructed very close to the junction ${ }^{23}$ H ow ever, at low er frequencies (typically below 10 M Hz ) the junction $w i l l$ see an im pedance corresponding to the bias resistor $R$ at the top of the cryostat, which can be chosen large enough to give $Q>1$. The sim plest circuit which captures the frequency dependence described above, is a JJ shunted by a series com bination of a resistor $R_{2}$ and a capacitor $C_{2}$ in parallel $w$ th the resistor $R_{1}$ as shown in $g$. 1 (b). At high frequencies where $C_{2}$ is essentially a short, the circuit is described by the highfrequency quality factor $Q_{1}=!_{p} R_{j j} C_{J}$, where $R_{j j}$ is the parallel com bination of $R_{1}$ and $R_{2}$. At low frequencies where $C_{2}$ e ectively blocks, the quality factor reads $Q_{0}=!{ }_{p} R_{1} C_{J} . T$ his $m$ odel has been studied previously by severalauthors $15,19,24,25,26$ C asting such a circuit in a m ore m athem atical language, it can be described by the coupled di erential equations ${ }^{19,25}$

$$
\begin{align*}
& -=\frac{Q_{1}}{Q_{0}} \frac{1}{E_{J}} \frac{d U()}{d}+v \frac{Q_{0}}{Q_{1}} 1+i_{n 1}+i_{n 2}  \tag{1}\\
& \underline{v}=\frac{Q_{1}}{Q_{0}^{3}} \quad \frac{1}{E_{J}} \frac{d U()}{d} \quad v+\dot{i}_{1}+i_{n 2} \frac{Q_{1}^{2}}{Q_{0}\left(Q_{0} Q_{1}\right)} ;
\end{align*}
$$

where $\mathrm{v}=\mathrm{V}_{\mathrm{C}}=\mathrm{R}_{1} \mathrm{I}_{0}$ is the reduced voltage across $\mathrm{C}_{2}$ and $=R_{1} C_{J}=R_{2} C_{2}$ re ects the value of the transition frequency, being ! $1=\mathrm{R}_{2} \mathrm{C}_{2}$, betw een high- and low im pedance regím es.

Phase space portraits for such a circuit are shown in gs. 2(c) and (d). Here the $y$-axis show $s$ the voltage $v$


F IG . 2: (C olor online) (a) T ilted washboard model. (b) Underdam ped circuit biased at $i_{r}<i<1$. (c) $C$ ircuit $w$ ith fre quency dependent dam ping and $Q_{1}>Q_{1 c}$ and with $Q_{1}<Q_{1 c}$ (d).
which is directly related to - . The topology of this phase portrait is also characterized by the coexistence of $x$ points A and the lim iting cycle B (not shown). H ow ever, for the param eters of $g$. 2 (c) $\left(Q_{0}=1: 85, Q_{1}=0: 036\right.$ and $i=0: 8$. ), the $0-b a s i n s$ and the 1 -basin are now separated by an unstable lim iting cycle C which does not intersect a saddle point. A n initial condition which is in nitesim ally below or above C w ill eventually end up either in an attractor $A$, or on $B$ respectively. In
g. 2 (c) we also see that the boundaries of the $0-b a s i n s$ are directly touching one another as a consequence of the existence of C.Thus, it is possible to have a tra jectory
 1-basin.

This sam eH F-overdam ped m odelcan how everproduce a new topology by sim ply low ering the high-frequency quality factor $Q_{1}$. As we increase the high frequency dam ping, the unstable lim iting cycle C slow ly approaches the saddle points $S$. For a critical value of $Q_{1}=Q_{1 c}, C$ and S willtouch and the phase-portrait suddenly changes its topology. F ig. (2)(d) show $s$ the phase space portrait for $Q_{0}=1: 85, Q_{1}=0: 0065<Q_{1 c}$ and $i=0: 8$ where we can see that $C$ disappears and adjacent 0 -state basins are again separated by the 1 -basin \{ a topology of the sam e form as the underdam ped RCSJ m odel.

## III. THESW ITCHING CURRENT DETECTOR

T he transition from the $0-b a s i n$ to the $1-b a s i n, ~ c a l l e d ~$ sw itching, can be used as a very sensitive detector. T he idea here is to choose a "hold" bias level and circuit param eters w here the phase space portrait has a favorable topology such as that shown in gs. 2(b) and (d). A rapid "sw itch pulse" is applied to the circuit bringing the system from A to a point as close as possible to the unstable point S. B alanced at this unstable point, the circuit $w$ ill be very sensitive to any extemal noise, or to the state of a qubit coupled to the circuit. The qubit state at the end of the sw itch pulse can be thought of as determ ining the initial condition, placing the ctitious phase particle on ether side of the basin boundary, from which the particle will evolve to the respective attractor. The speed and accuracy of the $m$ easurem ent $w$ ill depend on how rapidly the particle evolves aw ay from the unstable point $S$, far enough in to the $0-b a s i n ~ o r ~ 1-~$ basin such that extemal noise can not drive the system to the other basin. From this discussion it is clear that a phase space portrait $w$ th the topology show $n$ in $g$. 2(c) is not favorable for a sw itching current detector. H ere the sw itching corresponds to crossing the unstable cycle C. In itial conditions which are in nitesim ally close to C w ill rem ain close to $C$ overm any cycles of the phase, and thus a sm all am ount of noise can kick the system back and forth betw een the 0 -basins and the 1 boasin, leading to a longer $m$ easurem ent tim $e$ and increased num ber of errors.

The $m$ easurem ent tim $e$ is that tim e which is required
for the actual sw itching process to occur and must be shorter than the relaxation time of the qubit. In the ideal case the $m$ easurem ent time would be the sam e as the duration ofthe sw itch pulse. A m uch longertim em ay be required to actually determ ine which basin the system has chosen. This longer detection tim e is the duration of the hold levelneeded to reach a signalto noise ratio larger than 1, which is in practice determ ine by the bandw idth of the low -noise am pli er and lters in the second stage of the circuit. In our experim ents described in the follow ing sections, we used a low noise am pli er m ounted at the top of the cryostat which has a very lim ited bandw idth and high input im pedance. W hile this am pli er has very low back action on the qubit circuit (very low current noise), it's low bandw idth increases the detection time such that individualm easurem ents can be acquired only at < 10 kHz repetition rate. Since $m$ any $m$ easurem ents $\left(10^{4}\right)$ are required to get good statistics when $m$ easuring probabilities, the acquisition timewindow is some 0.5 seconds and the low frequency noise (drift or $1=\mathrm{f}$ noise) in the biasing circuit w ill thus play a role in the detector accuracy.

## IV. FLUCTUATIONS

Them easurem ent tim e ofa sw itching detector will depend on uctuations or noise in the circuit. The phase space portraits display the dissipative tra jectories of a dynam ical system, but they do not contain any in form ation about the uctuations which necessarily accom pany dissipation. For a sw itching current detector, we desire that these uctuations be as sm allas possible, and therefore the dissipative elem ents should be kept at as low a tem perature as possible. A nalyzing the sw itching current detector circuit w ith a therm alequilibrium m odel, we can calculate the rate of escape from the attractor A. This equilibrium escape rate how ever only sets an upper lim it on the $m$ easurem ent time. W hen we apply the sw itch pulse, the goal is to bring the circuit out of equilibrium, and we desire that the sensitivity at the unstable point be large enough so that the $m$ easurem ent is $m$ ade before equilibrium is achieved (i.e. before them al uctuations drive the sw itching process).

Equilibrium uctuations can cause a JJ circuit to jum p out of it's basin of attraction in a process know as therm alescape. The random force which gives rise to the escape tra jectory willm ost likely take the system through the saddle point $S$, because such a tra jectory would require a m inim um of energy from the noise source. ${ }^{21}$ For the topology of phase space portraits show $n$ in gs. 2(b) and (d), therm al escape will result in a sw itching from a $0-b a s i n$ to the $1-b a \sin$, w th negligible probability of a "retrapping" event bringing the system back from the 1basin to a $0-b a s i n$. H ow ever, for the topology of $g$. 2 (c), them alescape through the saddle point leads to another $0-b a \sin$, and thus the particle is im $m$ ediately retrapped in the next $m$ inim um of the washboard potential. This
process of successive escape and retrapping is know as phase di usion, and it's signature is a non-zero D C voltage across the JJ circuit when biased below the critical current, i< 1.

Phase di usion can occur in the overdam ped RCSJ m odel, or in the HF-overdam ped model when param eters result in a phase space topology of $g$. 2 (c). In the latter case, a sw itching process can be identi ed which corresponds to the escape from a phase di usive state to the free running state, or to crossing the unstable lim iting cycle $C$ in $g$. 2 (c) which $m$ arks the boundary between the phase di usive region and the $1-b a \sin$. This basin boundary $C$ is form ed by the convergence ofm any trajectories leading to di erent $S$, and the escape process of crossing this boundary is fundam entally di erent than escape from a $0-b a \sin$ to the 1 -basin. Num erical sim ulations ${ }^{19,27,28}$ of sw itching in JJs with such a phase space topology show that escape over the unstable boundary C is characterized by late sw itching events, which arise because even a sm all am ount of noise near this boundary can kick the system back and forth betw een the 1 -basin and the $m$ any 0 -basins for a long time before there is an actual escape leading to the lim iting cycle B.

The rate of them al escape from a $0-b a s i n ~ c a n ~ b e ~ c a l-~$ culated using K ram ers' form ula ${ }^{22,29,30}$

$$
\begin{equation*}
=\frac{!_{0}}{2} \exp \left(\quad E=k_{B} T\right) ; \tag{2}
\end{equation*}
$$

with E being the depth of the potentialw ell from A to $S, k_{B}$ Boltzm ann's constant and $T$ the tem perature. $T$ he prefactor $!0=2$ is called the attem pt frequency, where
$<1$ is a factor which depends on the dam ping. A nalytical results for were found by $K$ ram ers in the two lim iting cases of underdam ped $(Q>1)$ and overdam ped ( Q < 1) dynam ics. For the application of K ram ers' escape theory we require that $\mathrm{E} \quad \mathrm{k}_{\mathrm{B}} \mathrm{T}$, i.e. therm al escape is rare, so that each escape event is from a therm al equilibrium situation. The uctuations in them al equilibrium are com pletely uncorrelated in tim e, which is to say that the strength of the uctuations are frequency independent (white noise). Furtherm ore, the K ram ers form ula assum es absorbing boundary conditions, where the escape process which leads to a change of the basin of attraction has zero probability of retum. T hese conditions restrict the direct application ofK ram ers form ula in describing sw itching in JJ circuits ${ }^{31}$ to the case of the underdam ped RCSJm odelsuch as that depicted in g.2(b). In principle one could apply K ram ers form ula to the overdam ped RCSJ m odel, where the escape is from one well to the next well (sw itching betw een adjacent attractors A), but experim ents thus far are unable to $m$ easure a single 2 jump of the phase, as this corresponds to an extrem ely sm all change in circuit energy.

Therm al induced switching of sm all capacitance Josephson junctions which experience frequency dependent dam ping as m odeled by the circuit off ig. ⿴(b), was analyzed in experim ent and theory by the $Q$ uantronics
group ${ }^{15,26}$ who generalized K ram ers result. T he theoreticalanalysisw as sub ject to the constraint that the dynam ics of the voltage across the shunt capacitor $v$ is underdam ped (i.e. the quality factor $=\mathrm{R}_{2} \mathrm{R}_{\mathrm{jj}} \mathrm{C}_{2} \mathrm{I}_{0}={ }^{\prime}{ }_{0}\left(\mathrm{R}_{1}+\right.$ $R_{2}$ ) 1 where $R_{j j}$ is the parallel resistance of $R_{1}$ and $R_{2}$ ) so that the dynam ics of $v$ is sub ject to the fast-tim e average e ects of the uctuating phase . Separating tim escales in this way, the switching of $v$ could then be regarded as an escape out of a m eta-potential, B, form ed by the averaged uctuating force in the tilted w ashboard potential $F=i$ hsin $i \quad v$. Assum ing non-absorbing boundary conditions, this "escape over a dissipation barrier" can be w ritten as a generalization of $K$ ram ers' formula
$H$ ere $D(v)_{R_{v_{t}}}$ is the position-dependent di usion constant, and $B={\underset{v_{b}}{ }}^{(F=D) d v, w h e r e} v_{b}$ and $v_{t}$ stand for the bottom and the top of the e ective barrier, respectively. D etailed expressions can be found in refs. ${ }^{15,32}$

In section VI, we use these escape rate formulas to analyze pulse and hold switching m easurem ents. W e dem onstrate that long sw itching pulses lead to therm al equilibrium sw itching, whereas short pulses sw itch the circuit in a way that is independent of tem perature at low tem peratures, $w$ th the sw itching distribution deter$m$ ined by noise in the sw itch pulse rather than noise from the cooled dam ping circuit.

## V. EXPERIMENTS

Experim ents investigating junction current-voltage characteristics (IV C) as well as pulsed sw itching behavior w ere carried out in a dihution refrigeratorw ith 25 mK base tem perature. A block diagram of the $m$ easurem ent setup is shown in 9.3 (a). A low noise instrum entation am pli er (Burr-B rown $\mathbb{N}$ A 110, noise tem perature $1: 3 \mathrm{~K}$ at 10 kHz ) is $m$ easuring the voltage across the sam ple while the sam ple is biased by a room tem perature voltage source either via the bias capacitor $C_{b}$, or in series $w$ ith a bias resistor $R_{b}$. The capacitor bias $m$ ethod $w$ as used for experim ents w ith fast current pulses of duration $p=25 \mathrm{~ns}$, while the conventional resistor bias $m$ ethod was used for long pulse experim ents w th $p=20 \mu \mathrm{~s}$, as well as for IV C m easurem ents.

Three di erent sam ples are discussed in this paper which di er prim arily in the range of the measured sw itching current ( 3 nA to 120 nA ), and in the type of circuit used for the dam ping of the phase dynam ics. $T$ hese di erent dam ping circuits are labeled in the order in which they were im plem ented, and are represented in
g .3 (a) as the blocks $\mathrm{F}_{1} ; \mathrm{F}_{2} ; \mathrm{F}_{3} . \mathrm{T}$ hese environm ents can be $m$ odeled as RC lters $w$ th di erent cut-o frequencies, as schem atically be represented in g.3(b).
$T$ he key param eters for each sam ple are given in $T$ able 1. Sam ple I consisted of a C ooper pair transistor (C P T)

| Sam ple | Type | CPT |  |  | Shunt JJ |  |  | $\mathrm{F}_{1}$ |  | $\mathrm{F}_{2}$ |  | $\mathrm{F}_{3}$ |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | $\mathrm{E}_{\mathrm{J}}=\mathrm{E}_{\mathrm{c}}$ | $\mathrm{I}_{0}$ | $\mathrm{I}_{\text {sw }}$ | $\mathrm{E}_{\mathrm{J}}=\mathrm{E}_{\mathrm{C}}$ | $\mathrm{I}_{0}$ | $\mathrm{I}_{\text {sw }}$ | $\mathrm{R}_{1}$ | $\mathrm{C}_{1}$ | $\mathrm{R}_{2}$ | $\mathrm{C}_{2}$ | $\mathrm{R}_{3}$ | $\mathrm{C}_{3}$ |
| I | CPT | 32.9 | 58.5 | 3 | - | - | - | 60 | 1 | - | - | - | - |
| II | CPT | 29 | 51.6 | 42 | - | - | - | 60 | 1 | 72 | 024 | - | - |
| III | Q uantronium | 22 | 21 | 12 | 30.3 | 158 | 120 | 1000 | 3 | 72 | 0.24 | 600 | 1.4 |

C urrents are in [ nA ], resistances in [ ] and capacitances in [ nF ]
TABLE I: A n overview over the param eters for the three di erent sam ples. Filter $\mathrm{F}_{1}$ resem bles the cryostat leads or a cold SM D lter. $F$ ilter $F_{2}$ is the on-chip dam ping circuit and $F_{3}$ is an on-chip $R C$ - lter.

## (a)


(b)

(d)

(e)


FIG. 3: (a) B lock diagram of the experim ental setup. (b) Schem atic diagram of the $m$ odel used to describes the three di erent lters $\mathrm{F}_{1} ; \mathrm{F}_{2} ; \mathrm{F}_{3}$ which de ne the dam ping circuit. (c) $M$ icrograph of the sample show ing the two on-chip RC lters $F_{1}$ and $F_{2}$. (d) $M$ agni ed view of the center part of the chip, $F_{2}$ and the bias capacitor. (e) E lectron $m$ icroscope picture of the $Q$ uantronium (sample III).
em bedded in an environm ent de ned solely by the tw isted pair leads of the cryostat which is m odeled as $\mathrm{F}_{1}$. Sam ple II was a CPT fabricated in parallelw th Sam ple I, having nearly identical param eters, di ering only in that sam ple II was em bedded in a micro-fabricated on-chip HF-dam ping circuit $\mathrm{F}_{2}$. Sample III is a Q uantronium ${ }^{\frac{1}{1}}$ em bedded in the sam e HF-dam ping $F_{2}$ used w th sam ple II, but with an additional micro-fabricated on-chip low-pass leter $F_{3}$. The on-chip $R C$-environm ents $F_{2}$ and
$\mathrm{F}_{3}$ used for sam ples II and III and the bias capacitor were fabricated w ith a tw o-step optical lithography process. The capacitors w ere actually two capacitors in series, form ed by a plasm a-oxidized A 1 ground plane covered w ith a Au top plate. T he top plates are connected to the rest of the circuit via resistors which are form ed from the sameAu $m$ as the top plate, having a typical sheet resistance of $1: 2=2$. The capacitors of $\mathrm{F}_{3}$ could be $m$ easured quite accurately, from which we obtain a speci c capacitance of $13.6 \mathrm{fF} / \mathrm{\mu m}^{2}$ that is used to determ ine all on-chip capacitors. Figure 3(c) show s the essential parts of the chip and the com ponents de ning the high-frequency environm ent. T he bright rectangular area on the left side is the top plate of the capacitor, and the thin leads leading to the right are the resistors of
lter $F_{3}$. Figure 3 (d) show $s$ in detail the biasing capacitor $\mathrm{C}_{\mathrm{b}} \mathrm{T}$ he bright trapezoidal area on the left is the top plate of the capacitor $\mathrm{C}_{2}$ and the areas surrounded by dashed lines are dam ping resistors $\mathrm{R}_{2}=2$. F igure 3 (e) is an electron m icroscope picture show ing the $\mathrm{Al} / \mathrm{Al}_{2} \mathrm{O}_{3} / \mathrm{Al}$ tunnel junctions, which were fabricated in a third layer of electron beam lithography, w th the standard tw o-angle evaporation through a shadow mask. Figure 3(e) show s the quantronium circuit of sam ple III.


FIG. 4: IV curves of sam ple I w ithout designed RC environ$m$ ent (solid line) and of sam ple II w ith specially designed R C environm ent (dashed line).

The e ect of the on-chip HF dam ping from $F_{2}$ on the phase dynam ics as can be seen in $g .4$ where the IV C of sam ples I (solid line) and sam ple II (dashed line) are shown. These tw o CPT sam ples di er essentially by the presence ofF 2 in sam ple II. W e see that the typicalphase di usion shape of the $\operatorname{IVC} 33$ of sample $I$ is absent in sample II which shows a sharp supercurrent and hysteretic Sw itching. The presence of the on-chip environm ent in sam ple II e ectively reduces phase di usion as can be explained by a phase-space topology as show $n$ in gure 2(d). H ow ever, the very low value of $I_{\text {sw }}$ is a direct indication ofexcessive noise in the circuit. Therefore the on-chip low-pass ler $\mathrm{F}_{3}$ w as im plem ented in sam ple III, im proving the sw itching current to a value of $75 \%$ of the critical current. In the rem ainder of this paper we conœentrate on investigating the switching behavior of sam ple III.

The ability to suppress phase di usion opens up the possibility to study fast sw itching w ith H F-overdam ped phase dynam ics for the rst time. $W$ e used the pulse and hold $m$ ethod to $m$ easure $s w$ itching probabilities of sam ple III as a function of the am plitude of the sw itch pulse for tw o cases: A long pulse of $20 \mu \mathrm{~s}$ where the sw itching was found to be controlled by equilibrium them al escape, and a short pulse of 25 ns , where the sw itching is clearly a non-equilibrium process.

T he long pulses w ere form ed by applying a square voltage pulse through the bias resistor. The response to a sim ple square pulse is show $n$ in $g$.5(a), where the applied voltage pulse is shown, and several scope traces of the $m$ easured voltage over the CPT are overlayed. H ere we see that the sw itching causes an increase in the voltage over the sam ple which can occur at any tim e during the applied pulse. In order to do statistics we want to unam biguously count all sw itching events. Late sw itching events are di cult to distinguish from non-sw itching events as the voltage does not have tim e to rise above the noise level. W e can add a trailing hold level as shown in
g. 5(b). This hold level and duration m ust be chosen so that there is zero probability of sw itching on the hold part of the pulse. The response to such a pulse show s that it is now easy to distinguish $5 w$ itch from non-Sw itch events. In this case the hold level is used sim ply to quantize the output, and the sw itching which occurs during the initial sw itch pulse is found to be a them al equilibrium escape process as discussed below.

The fast pulses were formed with a new technique where a voltage waveform consisting of a sharp step followed by linear voltage rise is program $m$ ed in to an arbitrary w aveform generator. T he slope on the sharp step $(d V=d t)_{\text {pu lse }}$ is typically $6\{7$ tim es larger than the linear rise during the hold, $(d V=d t)_{\text {hold }}$. The voltage w aveform is propagated to the chip through a coax cable having negligible dispersion for the sharp 25 ns voltage step used. An on-chip bias capacitor $\mathrm{C}_{\mathrm{b}} \mathrm{w}$ illdi erentiate the voltage w aveform to give a sharp current pulse follow ed by a hold level, $I=C_{b} d V=d t$, which is show $n$ in $g .5(c)$. From the $m$ easured step am plitude needed to $s w$ itch the junction


FIG. 5: (a) Square pulse and response. (b) Sw itch pulse w ith hold leveland response. (c) Sw itch pulse w ith hold level and response, generated by the capacitive bias $m$ ethod. T he nite voltage in the non-sw itch case is due to the series lter resistance and the tw o-point $m$ easurem ent setup.
and the value of $C_{b}=1: 4 \mathrm{pF}$, we calculate a pulse am plitude of 360 nA through $\mathrm{C}_{\mathrm{b}}$. D ue to the sym $m$ etry of the
lter stages $F_{1}$ to $F_{3}$, only half of this 25 ns pulse current owsthrough the junction, with the other half ow ing through the lter to ground. Thus the peak current through the junction during the $25 \mathrm{nspulse} I_{p}=180 \mathrm{nA}$, which is larger than $I_{0}$. Exceeding $I_{0}$ for this very short tim $e$ is not unreasonable, bearing in $m$ ind that the circuit is heavily overdam ped at high frequencies, and a strong kick will be needed to overcom e dam ping and bring the phase particle close to the saddle point.

The hold level for these fast pulses is $40 \mu \mathrm{~s}$,very m uch longer than the sw itch pulse, and its duration is set by the tim e needed for the response voltage to rise above the noise level. $T$ he rate of this voltage rise depends on the hold current levelbecause after the sw itch we are essentially charging up the second stage lter and leads, $\mathrm{F}_{3}$ and $F_{1}$, w ith the hold current, $I_{\text {hold }}=C_{b}(d V=d t)_{\text {hold }}=$ 56 nA . For the low level of hold current used in these experim ents, we can follow the voltage rise at the junction w th the 100 kHz bandw idth low noise am pli er at the top of the cryostat. Typically we tum o the hold current and reset the detector when the sam ple voltage is 30 $\mu \mathrm{V}$, so that the junction voltage is alw ays wellbelow the gap voltage $\mathrm{V}_{2}=400 \mu \mathrm{~V}$, and therefore quasi-particle dissipation during the hold can be neglected.

Pulsed sw itching $m$ easurem ents were perform ed were a sequence of $10^{3}$ to $10^{4}$ identical pulse-hold-reset cycles w as applied to the sam ple while recording the voltage response of the sam ple. A threshold levelw as used to distinguish sw itching events (1) from non-sw itching events (0) as depicted in $g$.6(a). Them axim um response voltage achieved during each cycle is found and a histogram of these values is plotted as seen in g.6(b). The hold leveland duration are adjusted so as to achieve a bim odal distribution in the histogram, w ith zero events near the threshold level, $m$ eaning that there is zero am biguity in determ ining a sw itch event from a non-sw itch event. We further check that the hold level itself, w ithout the leading sw itch pulse, gives no sw itches of the sam ple. T he
sequence of sw itching events is stored as a binary sequence $Y_{i}$ in tem poral order. From this sequence we can calculate the sw itching probability,

$$
\begin{equation*}
P=\frac{1}{N}_{i=1}^{X^{N}} Y_{i} \tag{4}
\end{equation*}
$$

and the auto-correlation coe cients,

$$
\begin{equation*}
r_{k}=\frac{P_{\substack{N \\ i=1_{P}}}^{P} \underset{\substack{N \\ i=1}}{ }\left(Y_{i}\right)(\bar{Y})\left(Y_{i+k}\right)}{\bar{Y})}: \tag{5}
\end{equation*}
$$

where $k$ is the "lag" betw een pulses. The auto-correlation is a particularly im portant check for statistical independence of each switching event. A plot of $r_{k}$ for $\mathrm{k}=1::: 1000$ is show n in gure 6(c) and the random ness and low levelof $r_{k}$ indicates that all sw itching events are not in uenced by any extemal periodic signal. $W$ hen the circuit is not working properly, pick up of spurious signals up to the repetition frequency of the $m$ easurem ent, clearly show s up as a periodic modulation in the autocorrelation $r_{k}$. Of particular im portance is the correlation coe cient for lag one $r_{1}$ which tells how neighboring sw itching events in uence one another. Fig.6(d) shows $r_{1}$ as a function of the wait time w between the end of the hold level and the start of the next sw itch pulse. For large values of ${ }_{w}, r_{1}$ uctuates around 0 not exceeding 0.05 , which show sthat any in uence of a sw itching or non-sw itching event on the follow ing $m$ easurem ent, is statistically insigni cant. As $w$ is decreased how ever, a positive correlation is observed, $w$ th $r_{1}$ increasing exponentially $w$ ith shorter w. Positive correlation indicates that a sw itching event (a "1") is m ore likely to be followed by another sw itching event. Fig. 6(d) shows a $t$ to correlation $r_{1}$ to the function

$$
\begin{equation*}
r_{1}=3: 345 \quad \exp \quad \frac{w}{33: 3 \mu \mathrm{~s}}: \tag{6}
\end{equation*}
$$

W e can extrapolate the $t$ to the time $=40: 25 \mu \mathrm{~s}$ $w$ here the auto-correlation becom es $r_{1}=1, m$ eaning that once the circuit sw itches it w illalw ays stay in the 1 -state. In our experience, increasing the capacitance of lter $F_{1}$ causes to increase, from which we infer that the increase in the correlation $r_{1}$ for short $w$ is resulting from errors w here the detector is not properly reset because it does not have tim e to discharge the environm ent capacitance before a new pulse is applied. For the experim ent show $n$ in gure 6 the tim e constant of the environm ent was estim ated to be $3 \mu \mathrm{~s}$. T hese observations indicate that it is necessary to bring the junction voltage very close to zero before the retrapping will occur, and the detector $w$ ill reset. For good statistics $m$ any pulses are required and a short duty cycle is desirable in order to avoid e ects from low frequency noise as discussed section III. By studying the correlation coe cient $r_{1}$ in this way, we can choose an optim alduty cycle.


FIG.6: (a) Response of the sam ple to a pulse sequence resulting in sw itches (1) and no-sw itches (0) of the sam ple. (b) P eak voltage obtained during a current pulse, indicating good separation betw een the sw itch and non-sw itch signal. (c) A utocorrelation function $r_{k}$. (d) Correlation coe cient $r_{1}$ vs. the wait tim e, with tted exponential decay function.

## V I. A N A LY SIS

The sw itching probabilities were thus m easured and the dependence on the am plitude of the sw itch pulse, P ( $I_{p}$ ) was studied as as a function of tem perature. E ach $m$ easurem ent ofP ( $I_{p}$ ) began $w$ ith a pulse sequences having pulse am plitude resulting in a sw itching probabilty $\mathrm{P}=0$, and the pulse am plitude was successively increased until $P=1$. $T$ he $m$ easurem ent produces an "S-curve" as shown in gure 7, where the experim ental data for the long pulse duration $p=20 \mu \mathrm{~s}$ is show n w ith crosses. The S-curves w ere taken at tem peratures 100, 200, 300, 400 and 500 m K (right to left) respectively.

W e com pare the $m$ easured data to theoretical predictions based on therm alescape as discussed in section $\mathbb{I V}$. $T$ he leer $F_{1}$ causes a rounding of the applied square voltage pulse, which is accounted for by calculating the escape probability for a tim e dependent current ${ }^{32}$,

$$
\begin{equation*}
P=1 \quad \exp \quad \frac{1}{d i=d t}_{0}^{Z_{i}}\left(i^{0}\right) d i^{0} \tag{7}
\end{equation*}
$$

where the escape rate can be found using either eqns. 2 or 3. The sim ulated $S$-curves using eqn. 3 are plotted in gure 7 as solid lines for the tem peratures corresponding to the $m$ easured data. Sam ple param eters


FIG . 7: Sw itching probability as a function of pulse height in the tem perature range $T=100 ; 200 ; 300 ; 400 ; 500 \mathrm{~m} \mathrm{~K}$ (right to left) for a pulse duration $p=20 \mu \mathrm{~s}$. C rosses show $m$ easured data and sim ulated data is show $n$ as solid lines.
used for this calculation are the $m$ easured bias (including lter) resistance $R_{1}=11600$, the $m$ easured high frequency dam ping resistor, $R_{2}=7: 2$, the high frequency dam ping capacitance $\mathrm{C}_{2}=0: 207 \mathrm{nF}$, the junction capacitance $C_{J}=30 \mathrm{fF}$, and the calculated critical current $I_{0}=148 \mathrm{nA}$. The critical current $I_{0}=148 \mathrm{nA}$ is not the bare critical current $I_{0}=158 \mathrm{nA}$ since the quantronium wasbiased at a $m$ agnetic eld such that a persistent current of 10 nA was ow ing in the loop. T hese param eters are all independently determ ined, and not adjusted to im prove the $t$. H ow ever, the capacitance of lter $F_{1}$ w as uncertain, having a nom inal value of 10 nF , and unknown tem perature dependence below 4 K . Cooling the sam e capacitance to 4 K , we observed a decrease of $\mathrm{C}_{1}$ by around $10 \%$. This capacitor $\mathrm{C}_{1}$ determ ines the rounding of the square voltage pulse, and thus the tim e dependence of the current applied to the junction. W e found that it was necessary to assum e $C_{1}=3 \mathrm{nF}$ in order for the sim ulations to agree $w$ ith experim ent. This low value of $C_{1}$ at low tem peratures is not unreasonable, as circuit sim ulationsw ith the nom inal value of 10 nF show ed that the initial pulse would not exceed the hold level, which clearly is not possible because excellent latching of the circuit w as observed.

From the experim ental and sim ulated S-curves, we dene the sw itching current of the sam ple as the pulse am plitude that gives $50 \%$ sw itching $P\left(I_{s w}\right)=0: 5$ and the resolution is de ned from the S-curve by $I=I_{p}(P=$ $0: 9) \quad \mp(P=0: 1)$. A com parison of experim ental and theoretical $I_{s w}$ vs. $T$ and $I=I s_{s w}$ vs. $T$ is show $n$ in
g. 8. W e see that the experim ental data for the long pulses (points $m$ arked by an X) are in reasonably good agreem ent $w$ ith the sim ulated values $w$ hen the theory of sw itching in an environm ent $w$ ith frequency dependent dam ping is used (escape from a m eta-potential, equation (3) which is plotted as a solid line in g.8(a). W e note that for the $20 \mu \mathrm{~s}$ pulses, escape occurs at bias currents i $0: 7$, where the phase space has a topology as show $n$ in gure 2(d). H ence we can neglect phase di usion and
escape is from a saddle point, so that the non-absorbing boundary condition assum ed in the theory is valid. For com parison, we use the overdam ped K ram ers form ula (equation (2) to sim ulate the $S$-curve and calculate $I_{\text {sw }}$ and $I$, which is show $n$ by the dashed line in $g$. 8. H ere the prefactor $(Q)$ is given in ref. ${ }^{25}$ and we have used the high frequency quality factor $Q_{1}=0: 027$ as determ ined by the resistor $R_{2}$ only. W e see that the $K$ ram ers formula overestim ates $I_{\text {sw }}$ by some $25 \%$ ( $\mathrm{g} \cdot 8(\mathrm{~B})$ ) and is worse than the sim ulation based on eqn. 3, in reproducing the tem perature dependence of I ( $g$. 8(b)). In fact, the experim ental data for the $20 \mu$ s pulses only show s a weak increase in I over the tem perature range studied, whereas both theoretical curves predict a slight in crease in I. Thus an equilibrium therm al escape $m$ odel explains the data for long, 20 us pulses reasonably well and the data is better explained by the theory of escape w ith frequency dependent dam ping, than by the sim pler theory em bodied in the overdam ped K ram ers form ula. H ow ever the correspondence w th the form er theory is not perfect. W e m ay explain these deviations as being due to the fact that the quality factor $=4: 49$ (see section IV) does not really satisfy the condition for validity of the theory, 1.

Experim ental data for the short pulses of duration $\mathrm{p}=25 \mathrm{~ns}$ generated by the capacitive bias m ethod is plotted in $g$. 8 as circles. H ere we see that the value of $I_{s w}$ is constant in the tem perature range studied, indicating that escape is not from a them al equilibrium state. For the ideal phase space topology, as shown in gure [2(d), the initial pulse would bring the phase particle arbitrarily close to the saddle point $S$ for the hold bias level. If the separation in to the basins of attraction occurs before therm alequilibrium can be established, we would not expect tem perature dependence of $I_{s w}$. In this case, the width of the sw itching distribution w ill be determ ined not by therm al uctuations, but by other sources of noise, such as random variation in the height of the sw itch pulse. These variations are signi cant because the 1 / f noise from the waveform generator $m$ ust be taken in to account when generating the train of pulses over the tim e w indow of the $m$ easurem ent which w as about 0.5 sec . In our experim ents how ever, we m ay not have achieved a constant hold level since the voltage ram $p$ from the waveform generator is not perfectly sm ooth. K now ing the bias capacitor we can calculate an average hold level of $i_{\text {hold }}=0: 35$, som ew hat low er than the critical value of $i_{\text {hold }}=0: 67$ necessary to achieve the phase space topology of gure 2(d). Nevertheless, we observe excellent latching of the circuit for these 25 ns sw itch pulses. W e conclude that the observed tem perature independence of $I_{s w}$, and the fact that $I_{s w}$ exceeds $I_{0}$ by $20 \%$ is consistent $w$ ith a very rapid sw itching of the junction.

W e can rule out excessive therm alnoise as a reason for the tem perature independent value of $I_{\text {sw }}$ for the short pulses. By $m$ easuring the gate voltage dependence of $I_{\text {sw }}$ as a function of the tem perature, a clear transition from


F IG . 8: Sw itching current norm alized to critical current (a) and relative resolution (b) of sam ple III. C rosses indicatem easured values for $p=20 \mu \mathrm{~s}$, solid and dashed lines are calculated values using a generalization of K ram ers' large friction result and K ram ens' original result, respectively. C ircles are $m$ easured values for $p=25 \mathrm{~ns}$.

2e to e periodicity w as observed in the tem perature range 250 m K to 300 m K . For the size ofthe superconducting island used in this experim ent, we can estim ate a crossover tem perature $T \quad 300 \mathrm{mK}$, above which the free energy di erence between even and odd parity goes to zero. 34 H ence, we know that the sample is in equilibrium with the them om eter below $T$, and therefore heating e ects that $m$ ight occur in the short pulse experim ents, can not explain the fact that the observed $I_{s w}$ is independent of tem perature.

Thus we have achieved a very rapid, $25 \mathrm{~ns} m$ easure$m$ ent tim e of the sw itching current, which should be su cient form easurem ent of the quantum state of a quantronium circuit. For qubit readout, not only the m easure$m$ ent tim $e$ is im portant, but also the resolution of the detector. For the 25 ns pulse, we obtained the resolution of $I=I_{s w}=0: 055$, or $I=9: 9 n A$. This im plies that single shot readout is possible for a $Q$ uantronium $w$ ith param eters $\mathrm{E}_{\mathrm{C}}=0: 5 \mathrm{~K}$ and $\mathrm{E}_{\mathrm{J}}=\mathrm{E}_{\mathrm{C}}=2: 5$ where the
sw itching current of the two qubit states at the optim al readout point di er by 9.6 nA . N um erous experim ents were $m$ ade $w$ ith $m$ icrow ave pulses and continuous $m$ icrow ave radiation to try and nd the qubit resonance. H ow ever, due in part to uncertainty in the qubit circuit param eters (level separation) and in part to jumps in background charge, no qubit resonance was detected in these experim ents.

VII. CONCLUSION

Fast and sensitive $m$ easurem ent of the sw itching current can be achieved $w$ ith a pulse-and-hold $m$ easurem ent $m$ ethod, where an initial sw itch pulse brings the JJ circuit close to an unstable point in the phase space of the circuit biased at the hold level. This technique exploits the in nite sensitivity of a non-linear dynam ical system at a point of bifurcation, a com $m$ on them $e$ in $m$ any successfiul JJ qubit detectors. W e have show $n$ that w ith properly designed frequency dependent dam ping, fast sw itching can be achieved even when the high frequency dynam ics of the JJ circuit are overdam ped. W ith an on-chip RC dam ping circuit, we have experim entally studied the therm alescape process in overdam ped JJs. A capacitorbiasm ethod was used to create very rapid 25 ns sw itch pulses. W e dem onstrated fast sw itching in such overdam ped JJs for the rst tim e, where the Sw itching was not described by them al equilibrium escape. The $m$ ethods presented here are a sim ple and inexpensive w ay to perform sensitive $s w i t c h i n g$ current $m$ easurem ents in Josephson junction circuits. W hile we have shown that the sensitivity can be high, the e ect of back-action of such a detector is still unclear and $m$ ight be a reason why no quantum e ects were observed. In contrast to the readout strategy presented here, all other working qubit-readout strategies, both static sw itching and dispersive, are based on underdam ped phase dynam ics.

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